


<b>Search Notes</b>  	<b>Application/Control No.</b>  10564287	<b>Applicant(s)/Patent Under Reexamination</b>  FUCHIKAMI, RYUJI
	<b>Examiner</b>  Ryan D Coyer	<b>Art Unit</b>  2197

SEARCHED			
Class	Subclass	Date	Examiner
714	38	10/3/2011	RDC
717	130-131	10/3/2011	RDC
726	22-25 (keyword limited)	10/3/2011	RDC

SEARCH NOTES		
Search Notes	Date	Examiner
PLUS Search	10/3/2011	RDC
EAST Search	10/3/2011	RDC
Inventor Name & Double Patenting Search	10/3/2011	RDC
NPL Search - IEEE, ACM, Google Scholar; Keywords: buffer overflow, illegal memory access detection, memory security, stack smashing	10/3/2011	RDC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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